

**Search Notes**

Application/Control No.

10/705,818

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

NAKAYAMA ET AL.

Art Unit

2683

**SEARCHED**

Class	Subclass	Date	Examiner
455	411	8/19/2005	CH
380	201	8/19/2005	CH
713	169	8/19/2005	CH
340	573.1	8/19/2005	CH
455	41	8/19/2005	CH
713	156	8/19/2005	CH
705	041	8/19/2005	CH
709	223	8/19/2005	CH
370	432	8/19/2005	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IDS	8/19/2005	CH
Class/Subclass/Citation/Combined Text searched	8/19/2005	CH